

SCCS056 - August 1994 - Revised March 2000

## **Features**

- FCT-C speed at 4.6 ns
- · Power-off disable outputs permits live insertion
- Edge-rate control circuitry for significantly improved noise characteristics
- Typical output skew < 250 ps</li>
- ESD > 2000V
- TSSOP (19.6-mil pitch) and SSOP (25-mil pitch) packages
- Industrial temperature range of -40°C to +85°C
- $V_{CC} = 5V \pm 10\%$

#### CY74FCT16500T Features:

- · 64 mA sink current, 32 mA source current
- Typical  $V_{OLP}$  (ground bounce) <1.0V at  $V_{CC}$  = 5V,  $T_A$  = 25°C

#### CY74FCT162500T Features:

- · Balanced 24 mA output drivers
- Reduced system switching noise
- Typical  $V_{OLP}$  (ground bounce) <0.6V at  $V_{CC}$  = 5V,  $T_A$  = 25°C

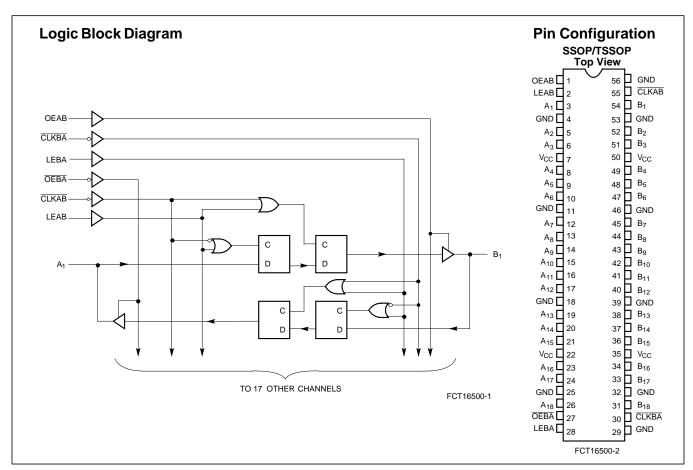
# 18-Bit Registered Transceivers

## **Functional Description**

These 18-bit universal bus transceivers can be operated in transparent, latched, or clock modes by combining D-type latches and D-type flip-flops. Data flow in each direction is controlled by output-enable (OEAB and OEBA), latch enable (LEAB and LEBA), and clock inputs (CLKAB and CLKBA) inputs. For A-to-B data flow, the device operates in transparent mode when LEAB is HIGH. When LEAB is LOW, the A data is latched if CLKAB is held at a HIGH or LOW logic level. If LEAB is LOW, the A bus data is stored in the latch/flip-flop on the HIGH-to-LOW transition of CLKAB. OEAB performs the output enable function on the B port. Data flow from B-to-A is similar to that of A-to-B and is controlled by OEBA, LEBA, and CLKBA. The output buffers are designed with power-off disable feature that allows live insertion of boards.

The CY74FCT16500T is ideally suited for driving high-capacitance loads and low-impedance backplanes.

The CY74FCT162500T has 24-mA balanced output drivers with current limiting resistors in the outputs. This reduces the need for external terminating resistors and provides for minimal undershoot and reduced ground bounce. The CY74FCT162500T is ideal for driving transmission lines.





## **Pin Summary**

Name	Description
OEAB	A-to-B Output Enable Input
OEBA	B-to-A Output Enable Input (Active LOW)
LEAB	A-to-B Latch Enable Input
LEBA	B-to-A Latch Enable Input
CLKAB	A-to-B Clock Input (Active LOW)
CLKBA	B-to-A Clock Input (Active LOW)
Α	A-to-B Data Inputs or B-to-A Three-State Outputs
В	B-to-A Data Inputs or A-to-B Three-State Outputs

## Function Table<sup>[1, 2]</sup>

	Inputs						
OEAB	LEAB	CLKAB	В				
L	Х	Х	Х	Z			
Н	Н	Х	L	L			
Н	Н	Х	Н	Н			
Н	L	ı	L	L			
Н	L	ı	Н	Н			
Н	L	Н	Х	B <sup>[3]</sup>			
Н	L	L	Х	B <sup>[4]</sup>			

# Maximum Ratings<sup>[5, 6]</sup>

(Above which the useful life may be impair guidelines, not tested.)	red. For user
Storage TemperatureCom'l -5	5°C to +125°C
Ambient Temperature with Power AppliedCom'l -5:	5°C to +125°C
DC Input VoltageC	0.5V to +7.0V
DC Output Voltage	0.5V to +7.0V
DC Output Current (Maximum Sink Current/Pin)60	0 to +120 mA
Power Dissipation	1.0W
Static Discharge Voltage(per MIL-STD-883, Method 3015)	>2001V

# **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Industrial	-40°C to +85°C	5V ± 10%

# **Electrical Characteristics** Over the Operating Range

Parameter	Parameter Description Test Conditions		Min.	Typ. <sup>[7]</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage		2.0			V
V <sub>IL</sub>	Input LOW Voltage				0.8	V
V <sub>H</sub>	Input Hysteresis <sup>[8]</sup>			100		mV
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> =-18 mA		-0.7	-1.2	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>I</sub> =V <sub>CC</sub>			±1	μА
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> =Max., V <sub>I</sub> =GND.			±1	μА
I <sub>OZH</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =2.7V			±1	μА
I <sub>OZL</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =0.5V			±1	μА
I <sub>OS</sub>	Short Circuit Current <sup>[9]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =GND	-80	-140	-200	mA
Io	Output Drive Current <sup>[9]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =2.5V	-50		-180	mA
I <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> ≤4.5V <sup>[10]</sup>			±1	μА

### Notes:

- H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care. Z = HIGH Impedance. \( \tau \) = HIGH-to-LOW Transition.

  A-to-B data flow is shown, B-to-A data flow is similar but uses \( \overline{OEBA} \), LEBA, and \( \overline{CLKBA} \).

  Output level before the indicated steady-state input conditions were established.

  Output level before the indicated steady-state input conditions were established, provided that \( \overline{CLKAB} \) was LOW before LEAB went LOW.

  Operation beyond the limits set forth may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature

- Unused inputs must always be connected to an appropriate logic voltage level, preferably either  $V_{CC}$  or ground. Typical values are at  $V_{CC} = 5.0$ V,  $T_{A} = +25$ °C ambient. This parameter is specified but not tested. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

  10. Tested at +25°C.



# **Output Drive Characteristics for CY74FCT16500T**

Parameter	Description	Test Conditions	Min.	Typ. <sup>[7]</sup>	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> =Min., I <sub>OH</sub> =-3 mA	2.5	3.5		V
		V <sub>CC</sub> =Min., I <sub>OH</sub> =-15 mA	2.4	3.5		
		V <sub>CC</sub> =Min., I <sub>OH</sub> =-32 mA	2.0	3.0		
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> =Min., I <sub>OL</sub> =64 mA		0.2	0.55	V

# **Output Drive Characteristics for CY74FCT162500T**

Parameter	Description	Test Conditions	Min.	Typ. <sup>[7]</sup>	Max.	Unit
I <sub>ODL</sub>	Output LOW Current <sup>[9]</sup>	V <sub>CC</sub> =5V, V <sub>IN</sub> =V <sub>IH</sub> or V <sub>IL</sub> , V <sub>OUT</sub> =1.5V	60	115	150	mA
I <sub>ODH</sub>	Output HIGH Current <sup>[9]</sup>	V <sub>CC</sub> =5V, V <sub>IN</sub> =V <sub>IH</sub> or V <sub>IL</sub> , V <sub>OUT</sub> =1.5V	-60	-115	-150	mA
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> =Min., I <sub>OH</sub> =-24 mA	2.4	3.3		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> =Min., I <sub>OL</sub> =24 mA		0.3	0.55	V

# **Capacitance**<sup>[8]</sup> ( $T_A = +25^{\circ}C$ , f = 1.0 MHz)

Parameter	Description	Test Conditions	Typ. <sup>[7]</sup>	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	4.5	6.0	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	5.5	8.0	pF

# **Power Supply Characteristics**

Parameter	Description	Test Condition	ons	Typ. <sup>[7]</sup>	Max.	Unit
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>CC</sub> =Max.	V <sub>IN</sub> ≤0.2V, V <sub>IN</sub> ≥V <sub>CC</sub> −0.2V	5	500	μΑ
Δl <sub>CC</sub>	Quiescent Power Supply Current (TTL inputs HIGH)	V <sub>CC</sub> =Max.	V <sub>IN</sub> =3.4V <sup>[11]</sup>	0.5	1.5	mA
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>[12]</sup>	V <sub>CC</sub> =Max., One Input Toggling, 50% Duty Cycle, Outputs Open, OEAB=OEBA=V <sub>CC</sub> or GND	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	75	120	μA/MHz
I <sub>C</sub> Total Power Supply Current <sup>[13]</sup>	Total Power Supply Current <sup>[13]</sup>	V <sub>CC</sub> =Max., f <sub>0</sub> =10 MHz (CLKAB), f <sub>1</sub> =5 MHz, 50% Duty	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	0.8	1.7	mA
		Cycle, Outputs Open,	V <sub>IN</sub> =3.4V or V <sub>IN</sub> =GND	1.3	3.2	mA
	V <sub>CC</sub> =Max., f <sub>0</sub> =10 MHz, f <sub>1</sub> =2.5 MHz, 50% Duty	V <sub>IN</sub> =V <sub>CC</sub> or V <sub>IN</sub> =GND	3.8	6.5 <sup>[14]</sup>	mA	
	Cycle, Outputs Open, Eighteen Bits Toggling, OEAB=OEBA=V <sub>CC</sub> LEAB=GND	V <sub>IN</sub> =3.4V or V <sub>IN</sub> =GND	8.5	20.8 <sup>[14]</sup>	mA	

11. Per TTL driven input (V<sub>IN</sub>=3.4V); all other inputs at V<sub>CC</sub> or GND.

12. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

13. I<sub>C</sub> = I<sub>QUIESCENT</sub> + I<sub>INPUTS</sub> + I<sub>DYNAMIC</sub>
I<sub>C</sub> = I<sub>CC</sub>+ΔI<sub>CC</sub>D<sub>H</sub>N+I<sub>CC</sub>C(f<sub>0</sub>/2 + f<sub>1</sub>N<sub>1</sub>)
I<sub>CC</sub> = Quiescent Current with CMOS input levels
ΔI<sub>CC</sub> = Power Supply Current for a TTL HIGH input (V<sub>IN</sub>=3.4V)
D<sub>H</sub> = Duty Cycle for TTL inputs HIGH
N<sub>T</sub> = Number of TTL inputs at D<sub>H</sub>
I<sub>CC</sub> = Dynamic Current caused by an input transition pair (HI H or I HI )

Dynamic Current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero

Input signal frequency

= Number of inputs changing at f<sub>1</sub>

All currents are in milliamps and all frequencies are in megahertz.

14. Values for these conditions are examples of the I<sub>CC</sub> formula. These limits are specified but not tested.



# Switching Characteristics Over the Operating Range<sup>[15]</sup>

			CY74FCT	162500AT		16500CT/ 162500CT		Fig
Parameter	Description		Min.	Max.	Min.	Max.	Unit	Fig. No. <sup>[16]</sup>
f <sub>MAX</sub>	CLKAB or CLKBA frequency			150		150	MHz	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay A to B or B to A		1.5	5.1	1.5	4.6	ns	1, 3
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay LEBA to A, LEAB to B		1.5	5.6	1.5	5.3	ns	1, 5
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay CLKBA to A, CLKAB to B		1.5	5.6	1.5	5.3	ns	1, 5
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable Time OEBA to A, OEAB to B		1.5	6.0	1.5	5.4	ns	1, 7, 8
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time OEBA to A, OEAB to B		1.5	5.6	1.5	5.2	ns	1, 7, 8
t <sub>SU</sub>	Set-Up Time, HIGH or LOW A to CLKAB, B to CLKBA		3.0		3.0		ns	9
t <sub>H</sub>	Hold Time, HIGH or LOW A to CLKAB, B to CLKBA		0		0		ns	9
t <sub>SU</sub>	Set-Up Time, HIGH or LOW	Clock HIGH	3.0		3.0		ns	4
	A to LEAB, B to LEBA	Clock LOW	1.5		1.5		ns	4
t <sub>H</sub>	Hold Time, HIGH or LOW A to LEAB, B to LEBA		1.5		1.5		ns	4
t <sub>W</sub>	LEAB or LEBA Pulse Width HIGH		3.0		2.5		ns	5
t <sub>W</sub>	CLKAB or CLKBA Pulse Width HI	GH or LOW	3.0		3.0		ns	5
t <sub>SK(O)</sub>	Output Skew <sup>[17]</sup>			0.5		0.5	ns	

# **Ordering Information CY74FCT16500T**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.6	CY74FCT16500CTPACT	Z56	56-Lead (240-Mil) TSSOP	Industrial
	CY74FCT16500CTPVC/PVCT	O56	56-Lead (300-Mil) SSOP	

# **Ordering Information CY74FCT162500T**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.6	CY74FCT162500CTPVC	O56	56-Lead (300-Mil) SSOP	Industrial
	74FCT162500CTPVCT	O56	56-Lead (300-Mil) SSOP	
5.1	CT74FCT162500ATPVC	O56	56-Lead (300-Mil) SSOP	Industrial
	74FCT162500ATPVCT	O56	56-Lead (300-Mil) SSOP	

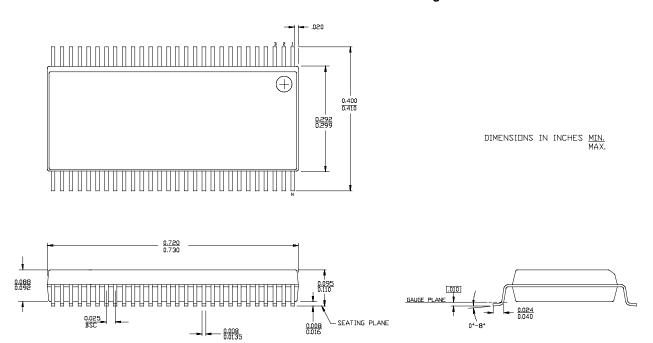
#### Notes:

- Minimum limits are specified but not tested on Propagation Delays.
   See "Parameter Measurement Information" in the General Information section.
   Skew between any two outputs of the same package switching in the same direction. This parameter is ensured by design.

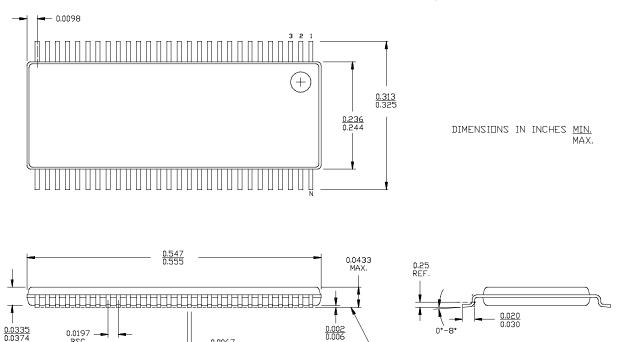


# **Package Diagrams**

## 56-Lead Shrunk Small Outline Package O56



## 56-Lead Thin Shrunk Small Outline Package Z56



SEATING PLANE

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